




Attorney Docket No. 02345/17A

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Rainer LOESCH, et al.
Serial No. : 09/750,837
Filed : December 28, 2000
Title : CALIBRATED SCALE IN THE NANOMETER RANGE
FOR TECHNICAL DEVICES USED FOR THE HIGH-
RESOLUTION OR ULTRAHIGH-RESOLUTION IMAGING
OF STRUCTURES
Art Unit : 1774
Examiner : Lawrence D. Ferguson

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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Date:	Feb. 20, 2007
Signature:	 Linda Shudy Lecomte (Reg. No. 47,084)

AMENDMENT ACCOMPANYING
REQUEST FOR CONTINUED EXAMINATION (RCE)

SIR:

In response to the Office Action made final dated January 11, 2006 and the Advisory Action dated July 28, 2006, please reconsider the above-identified application based on the following remarks.

Any Amendments to the Claims are reflected in the listing of claims, which begins on page 2 of this paper.

Remarks begin on page 5 of this paper.